

F-6971

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					Applicant: Seiichi HAYASHI, et al.			
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U.S. PATENT DOCUMENTS								
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
TRANSLATION KEY: * English Abstract. ^F Concise statement of relevance provided in foreign search report. ^C Concise statement of relevance provided in specification. ^G Concise statement of relevance provided in IDS. ^P Relevant portion of reference translated. ^O English abstract only - copy of reference in pct search.								
OTHER INFORMATION DISCLOSURE CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)								
		1997 - X-ray Reflectometer for the Diagnostics of Thin Films During Growth, U. Niggemeier, K. Lischka, W. M. Plotz and V. Holy, Journal of Applied Crystallography, Volume 30, Pages 905-908						
EXAMINER Hoon K. Song					DATE CONSIDERED			
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